

Flat Gain, High IP3

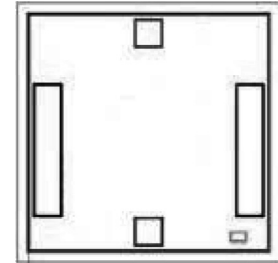
Monolithic Amplifier Die

GVA-62-D+

50Ω 0.01 to 6 GHz

The Big Deal

- Ultra Flat Gain
- Broadband High Dynamic Range without external Matching Components



Product Overview

GVA-62-D+ (RoHS compliant) is a wideband amplifier die fabricated using InGaP HBT technology and offers ultra flat gain over a broad frequency range and with high IP3. In addition, the GVA-62-D+, has good input and Output return loss over a broad frequency range without the need for external matching components and has demonstrated excellent reliability. It has repeatable performance from lot to lot has very good thermal performance.

Key Features

Feature	Advantages
Broad Band: 0.01 to 6.0 GHz	Broadband covering primary wireless communications bands: Cellular, PCS, LTE, WiMAX
Ultra Flat Gain ±0.5 dB over 50 to 4000 MHz ±0.20 dB over 700 to 2700 MHz	Eliminates need for gain flattening for most applications
High IP3 vs. DC power Consumption 32 dBm typical at 0.05 GHz 33.8 dBm typical at 0.8 GHz	The GVA-62-D+ matches industry leading IP3 performance relative and power consumption. The combination of the design and InGaP HBT Structure provides enhanced linearity over a broad frequency range. This feature makes this amplifier ideal for use in: <ul style="list-style-type: none">• Driver amplifiers for complex waveform up converter paths• Drivers in linearized transmit systems
No External Matching Components Required	GVA-62-D+ provides input and Output return loss of 12 to 17 dB up to 3 GHz without the need for external matching components, saving real estate and reducing component count.

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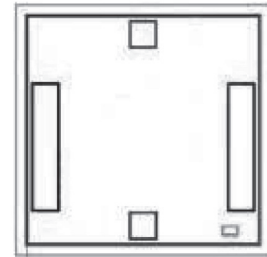
- Excellent Gain flatness, ± 0.5 dB over 50-4000 MHz
- Gain, 15.5 dB typ. at 0.8 GHz
- High POUT, P1dB 19.8 dBm typ. at 0.8 GHz
- High IP3, 33.8 dBm typ. at 0.8 GHz
- Excellent ESD protection, Class 1C for HBM
- No external matching components required

Typical Applications

- Base station infrastructure
- Portable Wireless
- CATV & DBS
- MMDS & Wireless LAN
- LTE

General Description

GVA-62-D+ (RoHS compliant) is an advanced wideband amplifier die fabricated using InGaP HBT technology offering high gain, excellent Gain flatness over a broad frequency range and high IP3. In addition, the GVA-62-D+ has good input and Output return loss over a broad frequency range without the need for external matching components.

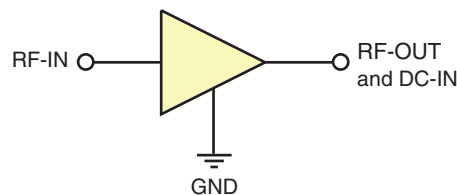


+RoHS Compliant

The +Suffix identifies RoHS Compliance. See our web site for RoHS Compliance methodologies and qualifications

Ordering Information: Refer to Last Page

Simplified Schematic and Pad description



Pad	Description
RF IN	RF input pad. This pad requires the use of an external DC blocking capacitor chosen for the frequency of operation.
RF-OUT and DC-IN	RF output and bias pad. DC voltage is present on this pad; therefore a DC blocking capacitor is necessary for proper operation. An RF choke is needed to feed DC bias without loss of RF signal due to the bias connection.
GND	Connections to ground.

Note: 1. Bond Pad material - Gold
2. Bottom of Die - Gold plated



Electrical Specifications¹ at 25°C unless noted

Parameter	Condition (GHz)	Min.	Typ.	Max.	Units
Frequency Range		0.01		6	GHz
Gain	0.05		16.5		dB
	0.8		15.5		
	2.0		15.7		
	3.0		15.9		
	4.0		15.8		
Gain flatness	0.05-4.0		±0.5		dB
	0.7-2.6		±0.2		
Input return loss	0.05		16.3		dB
	0.8		14.6		
	2.0		15.0		
	3.0		13.8		
	4.0		15.2		
Output return loss	0.05		12.5		dB
	0.85		16.7		
	2.0		15.2		
	3.0		12.5		
	4.0		9.7		
Reverse isolation	2.0		21.4		dB
	0.05		19.1		
	0.8		19.8		
	2.0		19.4		
	3.0		17.9		
Output power at 1dB compression	4.0		15.8		dBm
	6.0		12.0		
	0.05		32.2		
	0.8		33.8		
	2.0		32.8		
Output IP3	3.0		29.7		dBm
	4.0		27.2		
	6.0		23.8		
	0.05		4.8		
	0.8		5.1		
Noise figure	2.0		5.0		dB
	3.0		5.4		
	4.0		5.4		
	6.0		5.8		
	Supply Operating Voltage (Vcc)			5.0	
Device Operating Current		72	82	92	mA
Device Current Variation vs. Voltage			0.035		mA/V
Thermal Resistance, junction-to-ground lead			56		°C/W

1. Electrical Specifications are typical measured characteristics in Mini-Circuits die characterization test board. See Figure 1 for Test Circuit.

Absolute Maximum Ratings²

Parameter	Ratings
Operating Temperature	-40°C to 85°C
Junction Temperature	150°C
Operating Current at 5V	120 mA
Power Dissipation	0.725 W
Input Power (CW)	+24 dBm
DC Voltage at RF-OUT Pad ³	6V

- 2. Permanent damage may occur if any of these limits are exceeded. These maximum ratings are not intended for continuous normal operations. Die performance measured in industry standard SOT-89 package.
- 3. For continuous operation, do not exceed 5.2V

Characterization Test Circuit

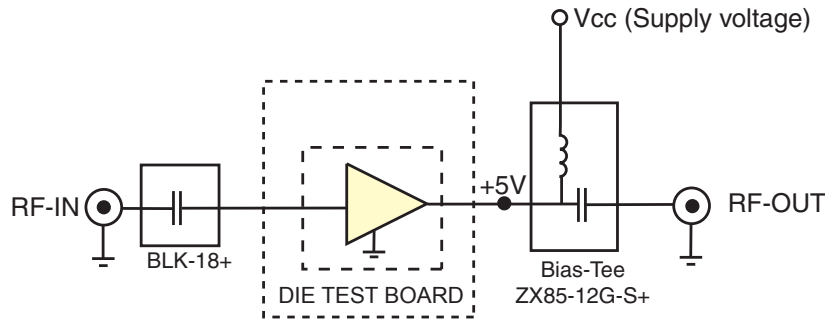


Figure 1: Block Diagram of Test Circuit used for characterization. Gain, Return loss, Output power at 1dB compression (P1 dB), output IP3 (OIP3) and Noise figure measured using Agilent’s N5242A PNA-X microwave network analyzer.

Conditions:

1. Gain and Return loss: Pad= -25dBm
2. Output IP3 (OIP3): Two tones, spaced 1 MHz apart, 0 dBm/tone at output.

Die Layout

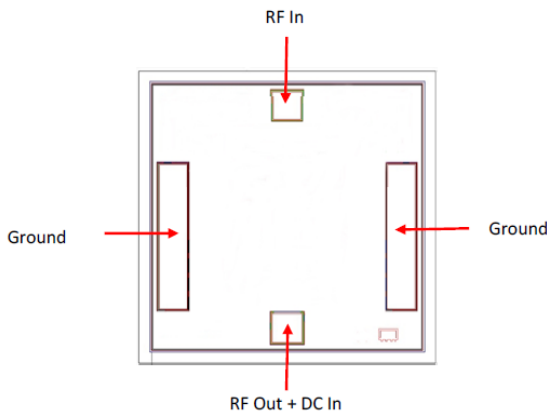


Fig 2. Die Layout

Bonding Pad Position
(Dimensions in μm , Typical)

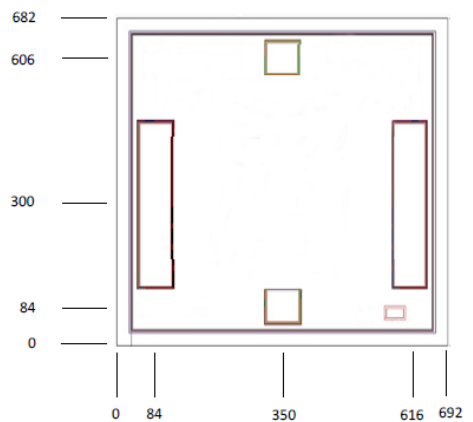


Fig 3. Bonding Pad Positions

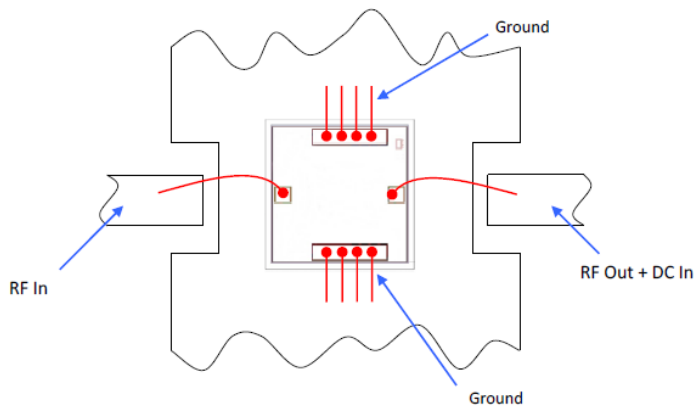
Critical Dimensions

Parameter	Values
Die Thickness, μm	100
Die Width, μm	692
Die Length, μm	682
Bond Pad Size(RF In, RF Out +DC In), μm	75 x 75
Bond Pad Size (Ground pads), μm	75 x 350

Assembly and Handling Procedure

- Storage**
 Dice should be stored in a dry nitrogen purged desiccators or equivalent.
- ESD**
 MMIC Gallium Arsenide (GaAs) amplifier dice are susceptible to electrostatic and mechanical damage. Die are supplied in antistatic protected material, which should be opened in clean room conditions at an appropriately grounded anti-static workstation. Devices need careful handling using correctly designed collets, vacuum pickup tips or sharp antistatic tweezers to deter ESD damage to dice.
- Die Attach**
 The die mounting surface must be clean and flat. Using conductive silver filled epoxy, recommended epoxies are DieMat DM6030Hk-PT/H579/H579 or Ablestik 84-1LMISR4. Apply sufficient epoxy to meet required epoxy bond line thickness, epoxy fillet height and epoxy coverage around total die periphery. Parts shall be cured in a nitrogen filled atmosphere per manufacturer's cure condition. It is recommended to use antistatic die pick up tools only.
- Wire Bonding**
 Bond pad openings in the surface passivation above the bond pads are provided to allow wire bonding to the dice gold bond pads. Thermosonic bonding is used with minimized ultrasonic content. Bond force, time, ultrasonic power and temperature are all critical parameters. Suggested wire is pure gold, 1 mil diameter. Bonds must be made from the bond pads on the die to the package or substrate. All bond wires should be kept as short as low as reasonable to minimize performance degradation due to undesirable series inductance.

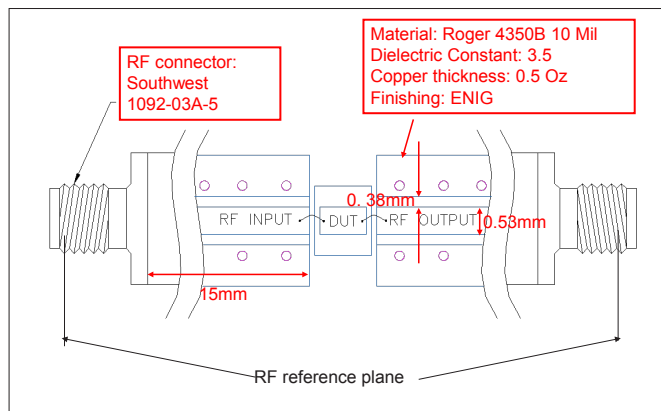
Assembly Diagram



Recommended Wire Length, Typical

Wire	Wire Length (mm)	Wire Loop Height (mm)
RF-IN, RF-OUT and DC-IN	0.6	0.15
GROUND	0.3	0.15

RF Reference Plane - No port extension



Additional Detailed Technical Information <i>additional information is available on our dash board.</i>	
Performance Data	Data Table
	Swept Graphs
	S-Parameter (S2P Files) Data Set with and without port extension(.zip file)
Case Style	Die
Die Ordering and packaging information	Quantity, Package Model No.
	Small, Gel - Pak: 10,50,100 KGD* GVA-62-DG+ Medium†, Partial wafer: KGD*<2255 GVA-62-DP+ Large†, Full Wafer GVA-62-DF+
	†Available upon request contact sales representative
	Refer to AN-60-067
Environmental Ratings	ENV-80

*Known Good Dice ("KGD") means that the dice in question have been subjected to Mini-Circuits DC test performance criteria and measurement instructions and that the parametric data of such dice fall within a predefined range. While DC testing is not definitive, it does help to provide a higher degree of confidence that dice are capable of meeting typical RF electrical parameters specified by Mini-Circuits.

ESD Rating**

Human Body Model (HBM): Class 1C (1000 to <2000V) in accordance with ANSI/ESD STM 5.1 - 2001

** Tested in industry standard SOT-89 package.

Additional Notes

- A. Performance and quality attributes and conditions not expressly stated in this specification document are intended to be excluded and do not form a part of this specification document.
- B. Electrical specifications and performance data contained in this specification document are based on Mini-Circuit's applicable established test performance criteria and measurement instructions.
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